

## 2SK3842

### Switching Regulator Applications, DC-DC Converter and Motor Drive Applications

- Low drain-source ON resistance:  $R_{DS(ON)} = 4.6 \text{ m}\Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 93 \text{ S}$  (typ.)
- Low leakage current:  $I_{DSS} = 100 \text{ }\mu\text{A}$  (max) ( $V_{DS} = 60 \text{ V}$ )
- Enhancement model:  $V_{th} = 2.0 \text{ to } 4.0 \text{ V}$  ( $V_{DS} = 10 \text{ V}$ ,  $I_D = 1 \text{ mA}$ )

### Absolute Maximum Ratings ( $T_a = 25^\circ\text{C}$ )

Characteristics	Symbol	Rating	Unit
Drain-source voltage	$V_{DSS}$	60	V
Drain-gate voltage ( $R_{GS} = 20 \text{ k}\Omega$ )	$V_{DGR}$	60	V
Gate-source voltage	$V_{GSS}$	$\pm 20$	V
Drain current	DC (Note 1)	$I_D$	A
	Pulse ( $t \leq 1 \text{ ms}$ ) (Note 1)	$I_{DP}$	
Drain power dissipation ( $T_c = 25^\circ\text{C}$ )	$P_D$	125	W
Single pulse avalanche energy (Note 2)	$E_{AS}$	322	mJ
Avalanche current	$I_{AR}$	75	A
Repetitive avalanche energy (Note 3)	$E_{AR}$	12.5	mJ
Channel temperature	$T_{ch}$	150	$^\circ\text{C}$
Storage temperature range	$T_{stg}$	-55 to 150	$^\circ\text{C}$

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc.).

### Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	$R_{th(ch-c)}$	1.0	$^\circ\text{C/W}$

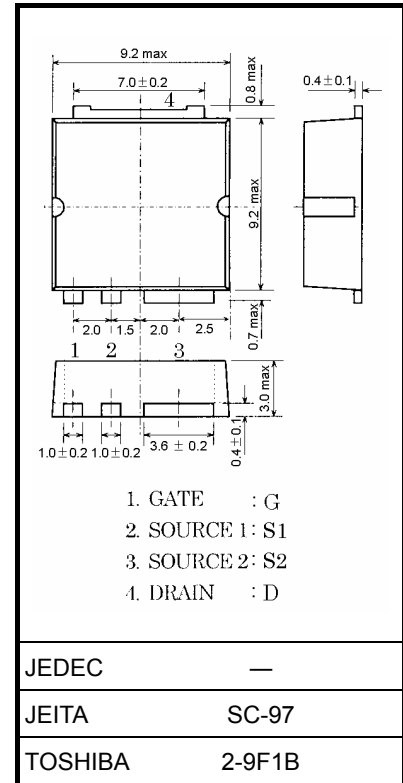
Note 1: Ensure that the channel temperature does not exceed  $150^\circ\text{C}$ .

Note 2:  $V_{DD} = 25 \text{ V}$ ,  $T_{ch} = 25^\circ\text{C}$  (initial),  $L = 78 \text{ }\mu\text{H}$ ,  $R_G = 25 \text{ }\Omega$ ,  $I_{AR} = 75 \text{ A}$

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Please handle with caution.

Unit: mm

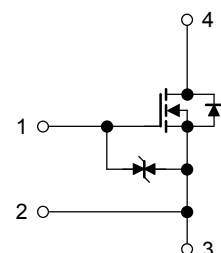


Weight: 0.74 g (typ.)

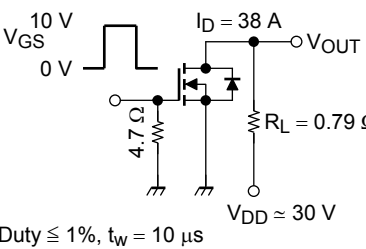
### Circuit Configuration

#### Notice:

Please use the S1 pin for gate input signal return. Make sure that the main current flows into S2 pin.



## Electrical Characteristics (Note 4) (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current		$I_{GSS}$	$V_{GS} = \pm 16 \text{ V}$ , $V_{DS} = 0 \text{ V}$	—	—	$\pm 10$	$\mu\text{A}$
Drain cut-OFF current		$I_{DSS}$	$V_{DS} = 60 \text{ V}$ , $V_{GS} = 0 \text{ V}$	—	—	100	$\mu\text{A}$
Drain-source breakdown voltage	$V_{(BR) DSS}$		$I_D = 10 \text{ mA}$ , $V_{GS} = 0 \text{ V}$	60	—	—	V
	$V_{(BR) DSX}$		$I_D = 10 \text{ mA}$ , $V_{GS} = -20 \text{ V}$	35	—	—	
Gate threshold voltage		$V_{th}$	$V_{DS} = 10 \text{ V}$ , $I_D = 1 \text{ mA}$	2.0	—	4.0	V
Drain-source ON resistance		$R_{DS(ON)}$	$V_{GS} = 10 \text{ V}$ , $I_D = 38 \text{ A}$	—	4.6	5.8	$\text{m}\Omega$
Forward transfer admittance		$ Y_{fs} $	$V_{DS} = 10 \text{ V}$ , $I_D = 38 \text{ A}$	46	93	—	S
Input capacitance		$C_{iss}$	$V_{DS} = 10 \text{ V}$ , $V_{GS} = 0 \text{ V}$ , $f = 1 \text{ MHz}$	—	12400	—	pF
Reverse transfer capacitance		$C_{rss}$		—	700	—	
Output capacitance		$C_{oss}$		—	1100	—	
Switching time	Rise time	$t_r$		—	18	—	ns
	Turn-ON time	$t_{on}$		—	45	—	
	Fall time	$t_f$		—	35	—	
	Turn-OFF time	$t_{off}$		—	200	—	
Total gate charge (gate-source plus gate-drain)		$Q_g$	$V_{DD} \approx 48 \text{ V}$ , $V_{GS} = 10 \text{ V}$ , $I_D = 75 \text{ A}$	—	196	—	nC
Gate-source charge		$Q_{gs}$		—	148	—	
Gate-drain ("miller") charge		$Q_{gd}$		—	48	—	

Note 4: Connect the S1 and S2 pins together, and ground them except during switching time measurement.

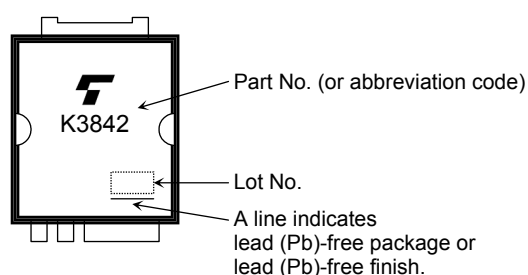
## Source-Drain Ratings and Characteristics (Note 5) (Ta = 25°C)

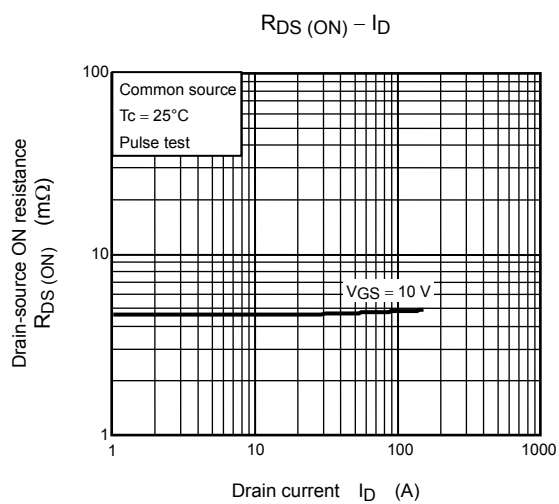
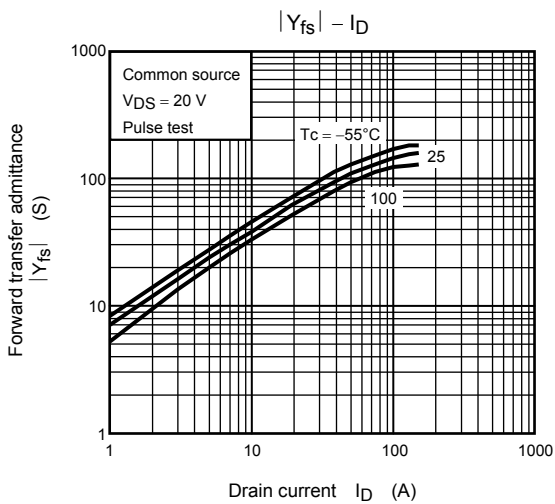
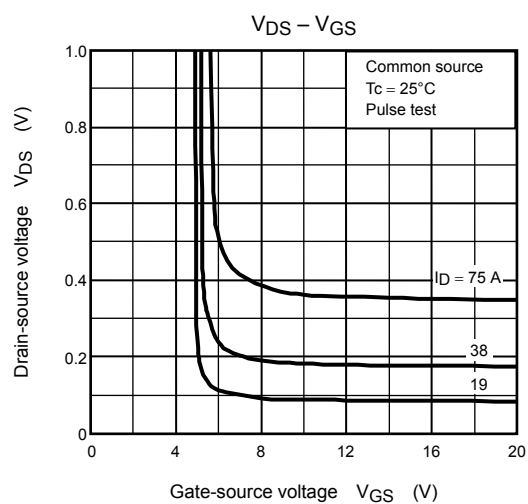
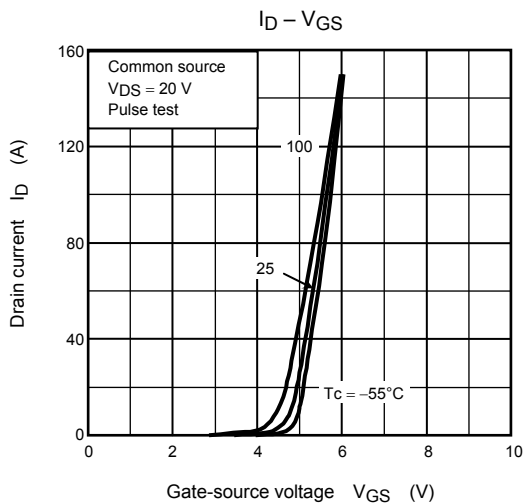
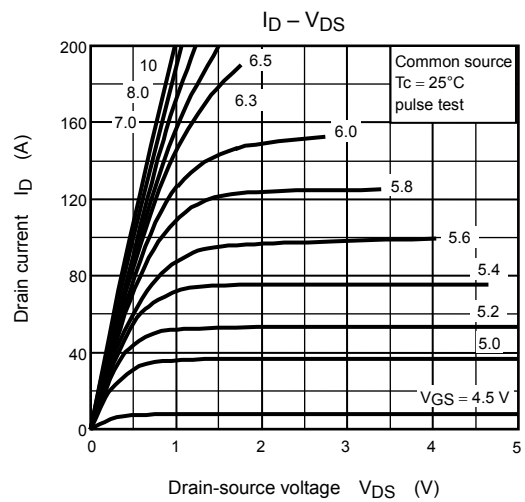
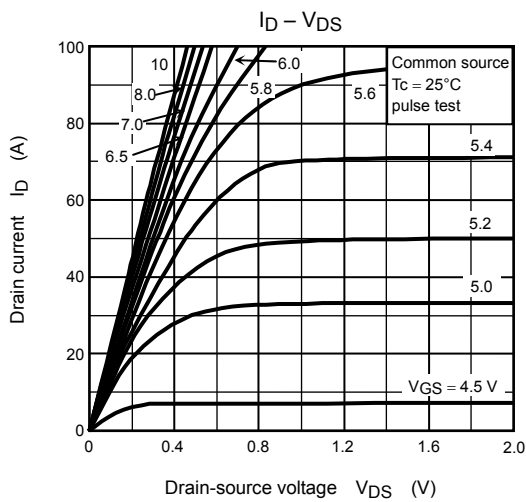
Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Continuous drain reverse current (Note 1, Note 5)	$I_{DR1}$	—	—	—	75	A
Pulse drain reverse current (Note 1, Note 5)	$I_{DRP1}$	—	—	—	300	A
Continuous drain reverse current (Note 1, Note 5)	$I_{DR2}$	—	—	—	1	A
Pulse drain reverse current (Note 1, Note 5)	$I_{DRP2}$	—	—	—	4	A
Forward voltage (diode)	$V_{DS2F}$	$I_{DR1} = 75 \text{ A}$ , $V_{GS} = 0 \text{ V}$	—	—	-1.7	V
Reverse recovery time	$t_{rr}$	$I_{DR} = 75 \text{ A}$ , $V_{GS} = 0 \text{ V}$ ,	—	70	—	ns
Reverse recovery charge	$Q_{rr}$	$dI_{DR}/dt = 50 \text{ A}/\mu\text{s}$	—	77	—	nC

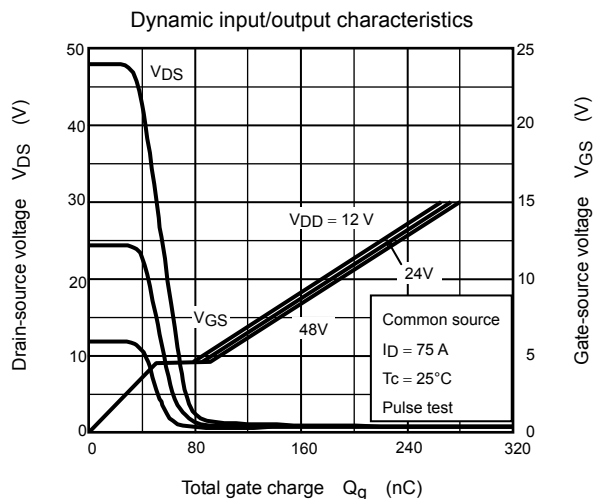
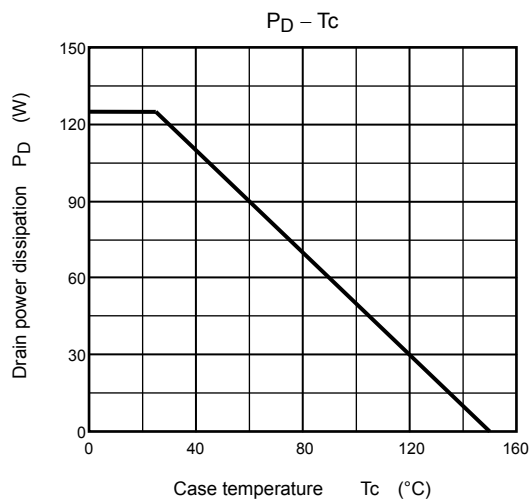
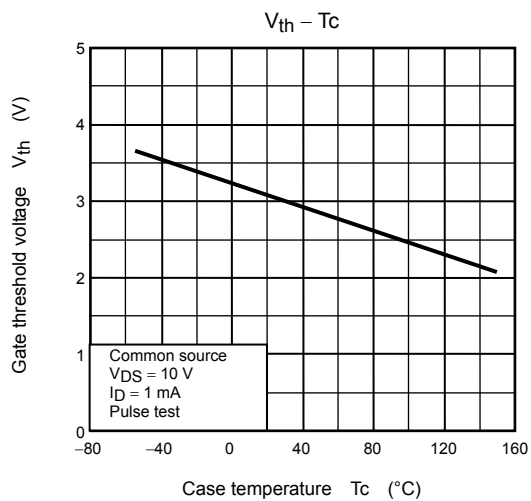
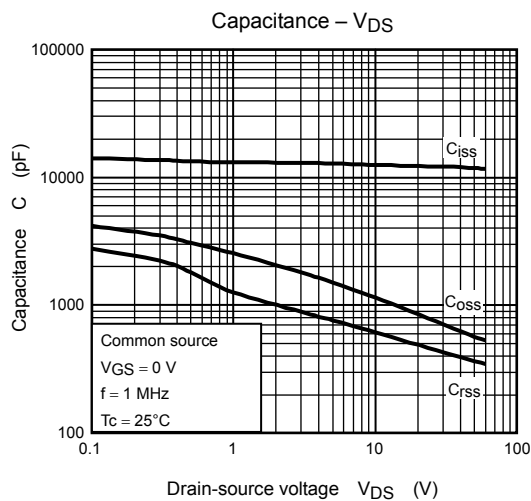
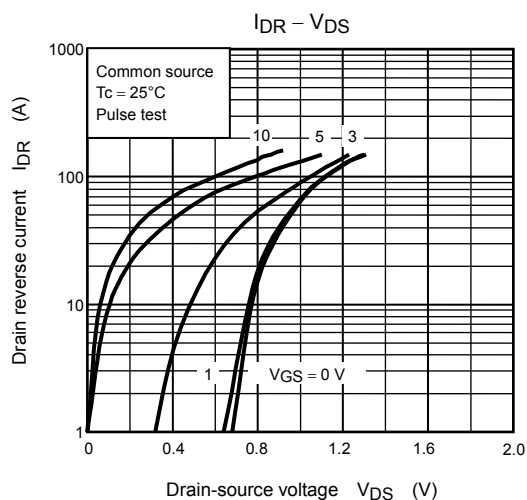
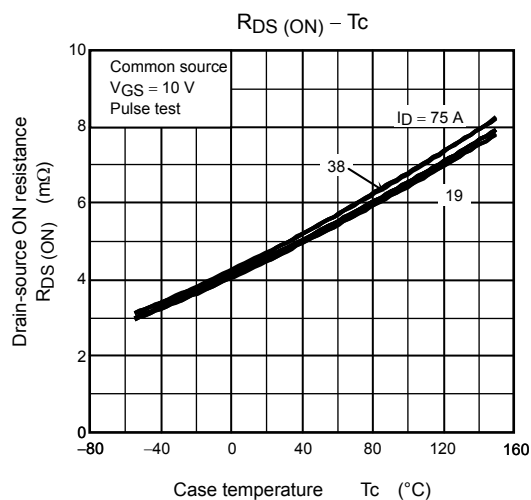
Note 5: Current flowing between the drain and the S1 pin, when open the S2 pin is left open.

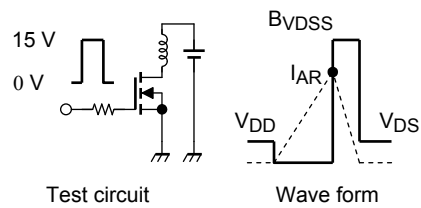
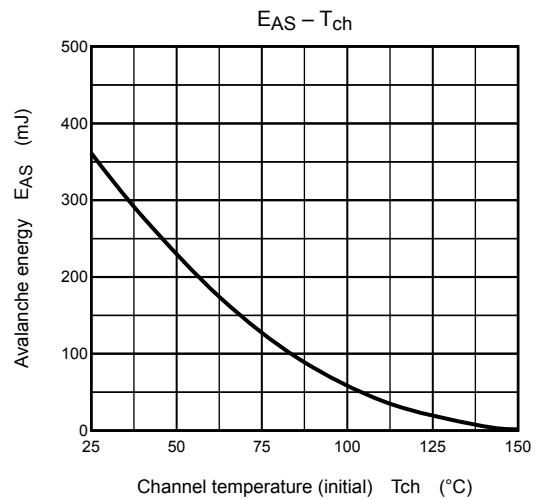
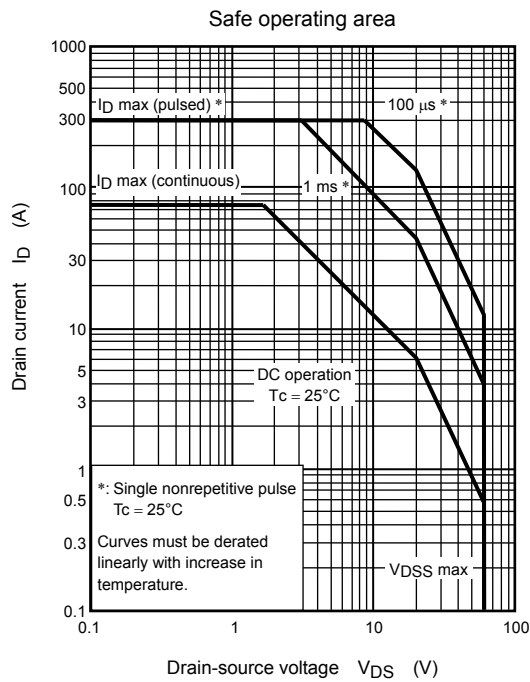
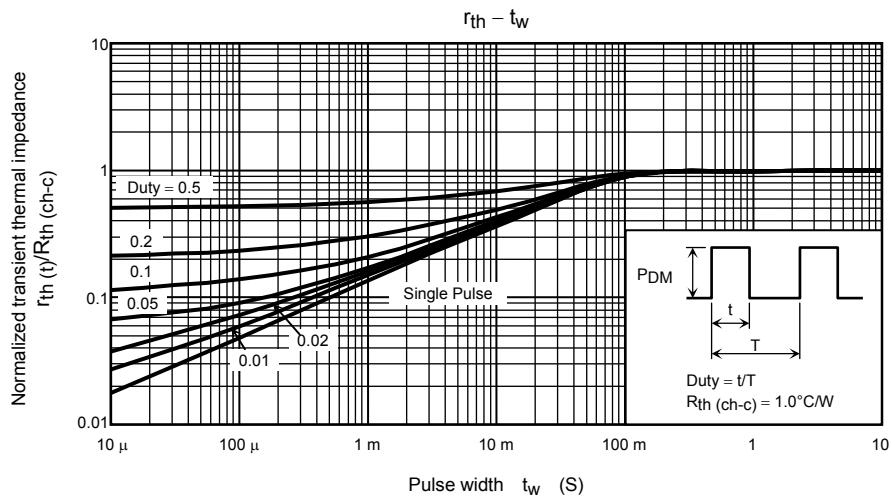
Unless otherwise specified, connect the S1 and S2 pins together, and ground them.

## Marking









$$R_G = 25 \, \Omega$$

$$V_{DD} = 25 \, V, L = 78 \, \mu H$$

$$E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left( \frac{BVDSS}{BVDSS - V_{DD}} \right)$$

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20070701-EN

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